OIPE JC174
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PATENT & TRADEMARK OFFICE

IRW

Docket No.: 070602-0156 **PATENT**

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of	:	Customer Number: 31824
Raymond M. Bell Jr., et al.	:	Confirmation Number: 2651
Serial No.: 10/680,720	:	Group Art Unit: 3662
Filed: October 06, 2003	:	Examiner: Not Yet Assigned
For: WAVEGUIDE-BASED OPTICAL INTERFEROMETER	:	

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed before the mailing date of a first Office Action on the merits. No certification or fee is required.

The Examiner's attention is directed to co-pending U.S. Patent Application Serial No. 10/051,122, filed January 22, 2002, which is directed to related technical subject matter. The identification of this U.S. Patent Application is not to be construed as a waiver of secrecy as to that application now or upon issuance of the present application as a patent. The Examiner is

respectfully requested to consider the cited application and the art cited therein during examination.

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 502203 and please credit any excess fees to such deposit account.

Respectfully submitted,

MCDERMOTT WILL & EMERY LLP

Mark J. Itri
Registration No. 36,171

18191 Von Karman Ave., Suite 400
Irvine, CA 92612-7107
949.851.0633 MJI:kk
Facsimile: 949.851.9348
Date: September 10, 2004
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INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(PTO-1449)

ATTY. DOCKET NO.	SERIAL NO.
070602-0156	**10/680,720**
APPLICANT: **Raymond M. Bell Jr., et al.**	
FILING DATE: **October 06, 2003**	GROUP: **Not Yet Assigned**

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code2 (if known)		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Code3-Number 4-Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	
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		T. KOBAYASHI, et al, "Optical FM Heterodyne Interferometry for Range and Displacement Measurements", CPEM '88 Digest, pp. 133-134 (1988).	
		M. TANAKA, et al., "Linear Interpolation of Periodic Error in a Heterodyne Laser Interferometer at Subnanometer Levels", IEEE Trans. Inst. & Meas., vol. 38, pp. 552-554 (1989).	
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		C. TUTTLE, "A Testbed for a Fiber-Optic Based Laser Metrology Gauge", Aug. 20, 2002, Interferometry in Space, Proceedings of SPIE Vol. 4852, pp. 717-730 (2003).	
		Laser Interferometers/Encoders & Laser-Based Calibration Systems: Laser Interferometer Position Systems Product Catalog, pp. 538-539 (1995).	
		"Optics and Laser Heads for Laser-Interferometer Position Systems" Product Overview, Agilent Technologies (1995).	

EXAMINER	DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.

ORC 346305-1.070602.0156